CLAIMS:

1.   A method for determining a pose of an implant object that is located inside a human or animal body, on the basis of a CAD model of that implant object through a reconstruction X-Ray procedure viz à viz the implant object,

said method being characterized by comprising for an implant object that has a
5   degree of symmetry according to an $\underline{n}$-dimensional structure of symmetry the steps of:

generating a first measurement configuration and a second measurement configuration regarding an X-Ray source and a prespecified implant object position, and generating a first and a second implant shadow, respectively;

assuming for each said first and second measurement configuration an
10   instance of said $\underline{n}$-dimensional structure of symmetry;

calculating for each of said first and second measurement configuration from said shadow a pair of alternative poses of said implant object as being symmetrical with respect to said $\underline{n}$-dimensional structure;

and finding among said pairs of alternative poses two matching poses that
15   thereby produce an angle information with respect to said n-dimensional structure of symmetry of said implant object.

2.   A method as claimed in Claim 1, wherein said $\underline{n}$-dimensional structure of mirror symmetry is a plane.
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3.   A method as claimed in Claim 1, wherein said $\underline{n}$-dimensional structure of symmetry is a straight line.

4.   A method as claimed in Claim 3, wherein said straight line is an axis of rotary
25   symmetry of said implant object.

5.   An apparatus being arranged for implementing a method as claimed in Claim 1 for determining a pose of an implant object that is located inside a human or animal body,

on the basis of a CAD model of that implant object through a reconstruction X-Ray procedure viz à viz the implant object,

said apparatus comprising for an implant object that has a degree of symmetry according to an $\underline{n}$-dimensional structure of symmetry the following facilities:

a measuring facility for generating a first measurement configuration and a second measurement configuration regarding an X-Ray source and a prespecified implant object position, and for generating a first and a second implant shadow, respectively;

data processing means for through assuming for each said first and second measurement configuration an instance of said $\underline{n}$-dimensional structure of symmetry and calculating for each of said first and second measurement configuration from said shadow a pair of alternative poses of said implant object as being symmetrical with respect to said $\underline{n}$-dimensional structure;

and matching means for finding among said pairs of alternative poses two matching poses that thereby produce an angle information with respect to said n-dimensional structure of symmetry of said implant object.